



Docket No.: 61282-060

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of	:	Customer Number: 20277
	:	
Sadami TAKEOKA, et al.	:	Confirmation Number: 2495
	:	
Serial No.: 10/766,951	:	Group Art Unit:
	:	
Filed: January 30, 2004	:	Examiner:
	:	
For: A METHOD FOR EVALUATING DELAY TESTS QUALITY	:	

**TRANSMITTAL OF FORMAL DRAWINGS**

Mail Stop Formal Drawings  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

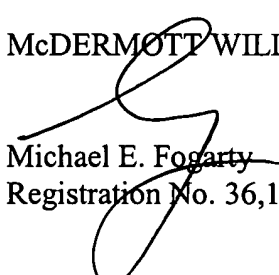
Sir:

At the time the above application was filed, informal drawings were presented with the application.

Submitted herewith are 11 sheet of the formal drawings.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP

  
Michael E. Fogarty  
Registration No. 36,139

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**Date: September 14, 2004**



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**TRANSMITTAL OF THE VERIFIED ENGLISH TRANSLATION  
FOR A NON-PROVISIONAL APPLICATION**

Box Missing Parts  
Commissioner for Patents  
Washington, DC 20231

Sir:

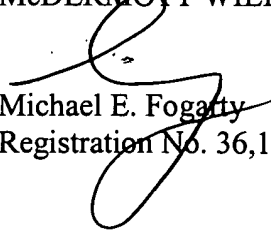
Submitted herewith are the following documents for filing in the above-referenced application:

1. Verified English Translation of the Non-Provisional Application

Submitted herewith are 44 sheets of the specification.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP

  
 Michael E. Fogarty  
 Registration No. 36,139

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 Washington, DC 20005-3096  
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PATENT APPLICATION  
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

*Sadami TAKEOKA et al.*

Appln. No.: 10/766,951

Group Art Unit:

Filed: January 30, 2004

Examiner:

For: Method for Evaluating Delay Test Quality

STATEMENT

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir/Madam:

I, Satoshi Watanabe, of Ark Mori Building, 13F, 12-32, Akasaka 1-chome, Minato-ku, Tokyo 107-6028, Japan, hereby state that:

I well understand the Japanese and English languages and attached is an accurate English translation made by me of the Japanese specification in the above-identified U.S. patent application.

Date : September 13, 2004

Name : Satoshi Watanabe

Satoshi WATANABE